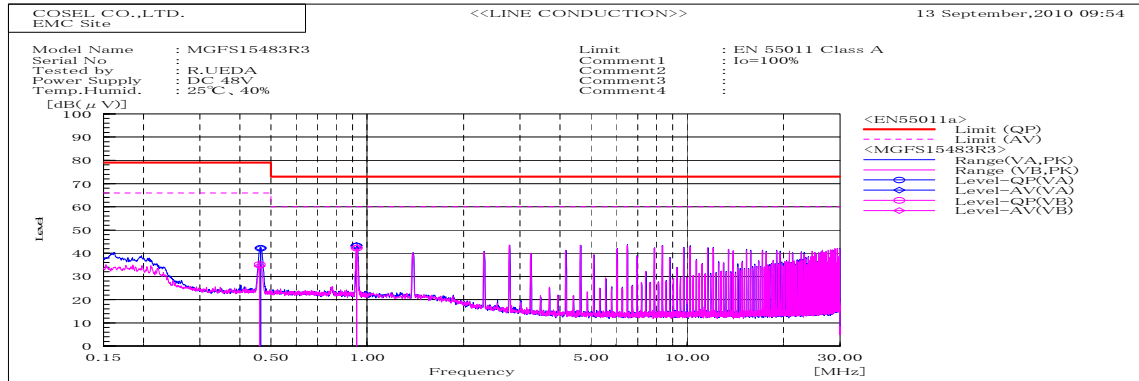
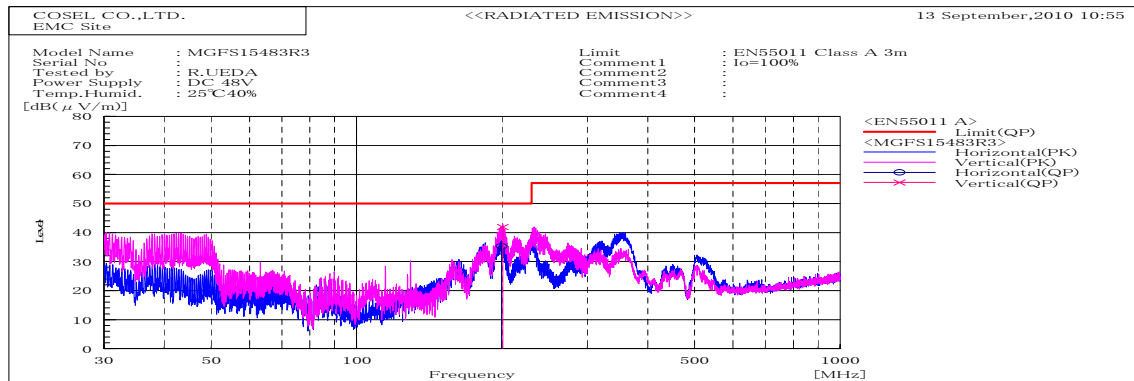


DATA SHEET		Date	21-Sep-10
Model	MGFS15483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46146		VB	25.2	24.4	10	35.2	34.4	79	66	43.8	31.6	Pass	
0.46445		VA	32.1	32.1	10.1	42.2	42.2	79	66	36.8	23.8	Pass	
0.92625		VA	33.1	33.2	10.1	43.2	43.3	73	60	29.8	16.7	Pass	
0.92708		VB	32.2	32.3	10	42.2	42.3	73	60	30.8	17.7	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP		QP	QP					
199.176	H	Stable	57.3	-22	35.3	50	14.7	Pass	127	24	
200.519	V	Stable	63.9	-22	41.9	50	8.1	Pass	122	209	

DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



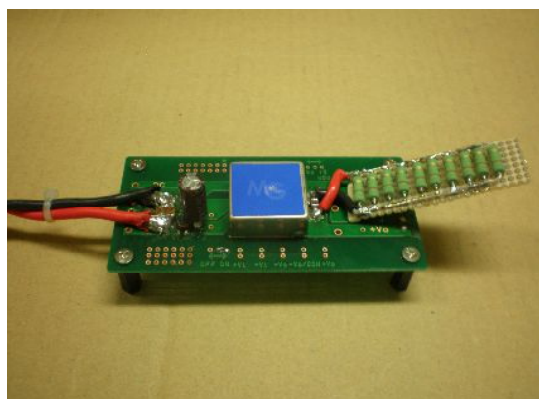


Conditions

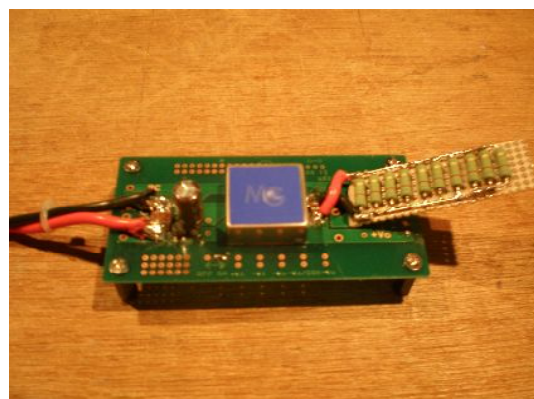
Test : EMI
Model Name : MGFS1548□□/MGFW1548□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

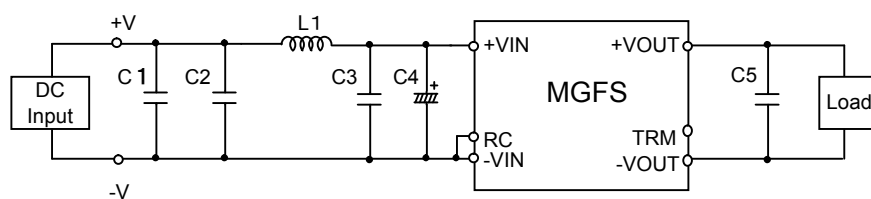


Fig.1 Testing circuitry 1

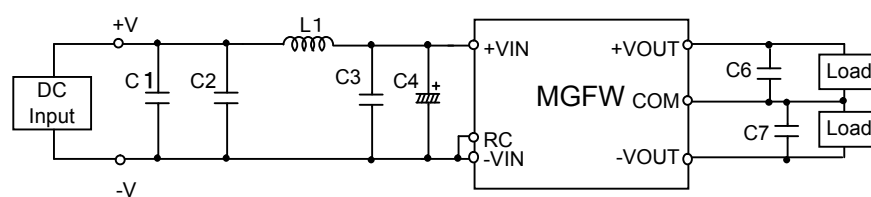


Fig.2 Testing circuitry 2

L1	: 10 μ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 μ F	C4532JB2A225MT (TDK)
C4	: 80V	47 μ F	LXV80VB47M (NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 μ F	CM32X5R226K25A (KYOCERA)